

# CY7C281A CY7C282A

#### Features

- CMOS for optimum speed/power
- High speed
  - —25 ns (commercial)
  - 30 ns (military)
- Low power
  - -495 mW (commercial)
  - 660 mW (military)
- EPROM technology 100% programmable
- Slim 300-mil or standard 600-mil DIP or 28-pin LCC
- + 5V  $\pm 10\%$  V<sub>CC</sub>, commercial and military
- TTL-compatible I/O
- Direct replacement for bipolar PROMs
- Capable of withstanding >2001V static discharge

## **Functional Description**

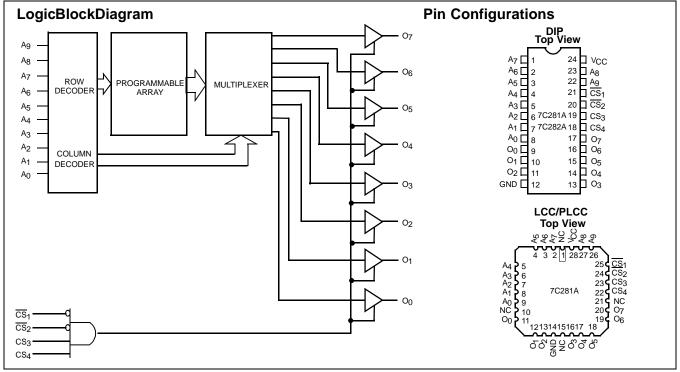
The CY7C281A and CY7C282A are high-performance 1024-word by 8-bit CMOS PROMs. They are functionally iden-

# 1K x 8 PROM

tical, but are packaged in 300-mil and 600-mil-wide packages respectively. The CY7C281A is also available in a 28-pin leadless chip carrier. The memory cells utilize proven EPROM floating-gate technology and byte-wide intelligent programming algorithms.

The CY7C281A and CY7C282A are plug-in replacements for bipolar devices and offer the advantages of lower power, superior performance, and programming yield. The EPROM cell requires only 12.5V for the super voltage, and low current requirements allow for gang programming. The EPROM cells allow each memory location to be tested 100% because each location is written into, erased, and repeatedly exercised prior to encapsulation. Each PROM is also tested for AC performance to guarantee that after customer programming, the product will meet DC and AC specification limits.

<u>Reading is accomplished by placing an active LOW signal on  $CS_1$  and  $CS_2$ , and active HIGH signals on  $CS_3$  and  $CS_4$ . The contents of the memory location addressed by the address lines  $(A_0-A_9)$  will become available on the output lines  $(O_0-O_7)$ .</u>



#### **Selection Guide**

		7C281A-25 7C282A-25	7C281A-30 7C282A-30	7C281A-45 7C282A-45
Maximum Access Time (ns)		25	30	45
Maximum Operating	Commercial	100	100	90
Current (mA)	Military		120	120



# **Maximum Ratings**

(Above which the useful life may be impaired. For user guidelines, not tested.)

Storage Temperature65°C to +150°C	)
Ambient Temperature with Power Applied55°C to +125°C	2
Supply Voltage to Ground Potential (Pin 24 to Pin 12)0.5V to +7.0V	/
DC Voltage Applied to Outputs in High Z State0.5V to +7.0V	/
DC Input Voltage3.0V to +7.0V	/
DC Program Voltage (Pins 18, 20)13.0\	/

Static Discharge Voltage	>2001V
(per MIL-STD-883, Method 3015)	
Latch-Up Current	>200 mA

## **Operating Range**

Range	Ambient Temperature	v <sub>cc</sub>
Commercial	0°C to +70°C	5V ±10%
Industrial <sup>[1]</sup>	–40°C to +85°C	5V ±10%
Military <sup>[2]</sup>	–55°C to +125°C	5V ±10%

Electrical Characteristics Over the Operating Range<sup>[3,4]</sup>

					1A-25 2A-25		1A-30 2A-30		1A-45 2A-45	
Parameter	Description	Test Cond	itions	Min.	Max.	Min.	Max.	Min.	Max.	Unit
V <sub>OH</sub>	Output HIGH Voltage	$V_{CC} = Min., I_{OH} = -4$	4.0 mA	2.4		2.4		2.4		V
V <sub>OL</sub>	Output LOW Voltage	$V_{CC} = Min., I_{OL} = 16$	6.0 mA		0.4		0.4		0.4	V
V <sub>IH</sub>	Input HIGH Level	Guaranteed Input Logical HIGH Voltage for All Inputs		2.0		2.0		2.0		V
V <sub>IL</sub>	Input LOW Level	Guaranteed Input Logical LOW Voltage for All Inputs			0.8		0.8		0.8	V
I <sub>IX</sub>	Input Current	$GND \leq V_{IN} \leq V_{CC}$		-10	+10	-10	+10	-10	+10	μA
I <sub>OZ</sub>	Output Leakage Current	$GND \leq V_{OUT} \leq V_{CC},$ Output Disabled		-10	+10	-10	+10	-10	+10	μA
I <sub>OS</sub>	Output Short Circuit Current <sup>[5]</sup>	V <sub>CC</sub> = Max., V <sub>OUT</sub> =	= GND	-20	-90	-20	-90	-20	-90	mA
I <sub>CC</sub>	Power Supply Current	V <sub>CC</sub> = Max.,	Commercial		100		100		90	mA
		$I_{OUT} = 0 \text{ mA}$	Military				120		120	
V <sub>PP</sub>	Program Voltage			12	13	12	13	12	13	V
V <sub>IHP</sub>	Program HIGH Voltage			3.0		3.0		3.0		V
V <sub>ILP</sub>	Program LOW Voltage				0.4		0.4		0.4	V
I <sub>PP</sub>	Program Supply Current				50		50		50	mA

# Capacitance<sup>[4]</sup>

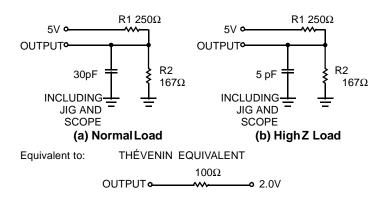
Parameter	Description	Test Conditions	Max.	Unit
C <sub>IN</sub>	Input Capacitance	$T_A = 25^{\circ}C, f = 1 \text{ MHz},$	10	pF
C <sub>OUT</sub>	Output Capacitance	$V_{CC} = 5.0V$	10	pF

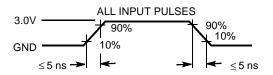
Note:

Contact a Cypress representative for industrial temperature range specifications.
T<sub>A</sub> is the "instant on" case temperature.
See the last page of this specification for Group A subgroup testing information.
See "Introduction to CMOS PROMs" in this Data Book for general information on testing.
For test purposes, not more than one output at a time should be shorted. Short circuit test duration should not exceed 30 seconds.



# AC Test Loads and Waveforms<sup>[4]</sup>

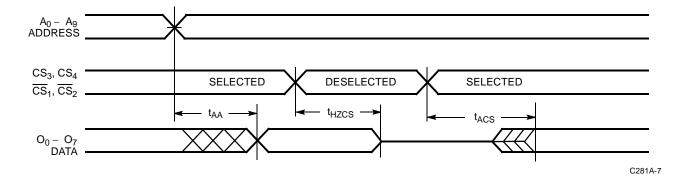




#### Switching Characteristics Over the Operating Range<sup>[3,4]</sup>

		7C28 7C28	1A-25 2A-25		1A-30 2A-30	7C28 7C28	1A-45 2A-45	
Parameter	Description	Min.	Max.	Min.	Max.	Min.	Max.	Unit
t <sub>AA</sub>	Address to Output Valid		25		30		45	ns
t <sub>HZCS</sub>	Chip Select Inactive to High Z		15		20		25	ns
t <sub>ACS</sub>	Chip Select Active to Output Valid		15		20		25	ns

## **Switching Waveforms**



#### **Programming Information**

Programming support is available from Cypress as well as from a number of third party software vendors. For detailed

programming information, including a listing of software packages, please see the PROM Programming Information located at the end of this section. Programming algorithms can be obtained from any Cypress representative.

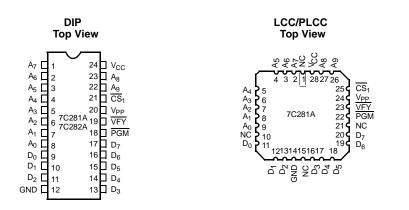


#### Table 1. Mode Selection

		Pin Function <sup>[6]</sup>						
	Read or Output Disable	A <sub>9</sub> –A <sub>0</sub>	CS4	CS <sub>3</sub>	CS <sub>2</sub>	CS <sub>1</sub>	0 <sub>7</sub> –0 <sub>0</sub>	
Mode	Other	A <sub>9</sub> –A <sub>0</sub>	PGM	VFY	V <sub>PP</sub>	CS <sub>1</sub>	D7-D0	
Read		A <sub>9</sub> -A <sub>0</sub>	V <sub>IH</sub>	V <sub>IH</sub>	V <sub>IL</sub>	V <sub>IL</sub>	O <sub>7</sub> –O <sub>0</sub>	
Output Disa	ble	A <sub>9</sub> -A <sub>0</sub>	Х	Х	V <sub>IH</sub>	Х	High Z	
Output Disa	ble	A <sub>9</sub> -A <sub>0</sub>	Х	V <sub>IL</sub>	Х	Х	High Z	
Output Disa	ble	A <sub>9</sub> -A <sub>0</sub>	V <sub>IL</sub>	Х	Х	Х	High Z	
Output Disa	ble	A <sub>9</sub> -A <sub>0</sub>	Х	Х	Х	V <sub>IH</sub>	High Z	
Program		A <sub>9</sub> -A <sub>0</sub>	V <sub>ILP</sub>	V <sub>IHP</sub>	V <sub>PP</sub>	V <sub>ILP</sub>	D <sub>7</sub> D <sub>0</sub>	
Program Ve	rify	A <sub>9</sub> -A <sub>0</sub>	V <sub>IHP</sub>	V <sub>ILP</sub>	V <sub>PP</sub>	V <sub>ILP</sub>	O <sub>7</sub> –O <sub>0</sub>	
Program Inh	nibit	A <sub>9</sub> -A <sub>0</sub>	V <sub>IHP</sub>	V <sub>IHP</sub>	V <sub>PP</sub>	V <sub>ILP</sub>	High Z	
Intelligent P	rogram	A <sub>9</sub> -A <sub>0</sub>	V <sub>ILP</sub>	V <sub>IHP</sub>	V <sub>PP</sub>	V <sub>ILP</sub>	D <sub>7</sub> D <sub>0</sub>	
Blank Checl	k	A <sub>9</sub> –A <sub>0</sub>	V <sub>IHP</sub>	V <sub>ILP</sub>	V <sub>PP</sub>	V <sub>ILP</sub>	Zeros	

Note:

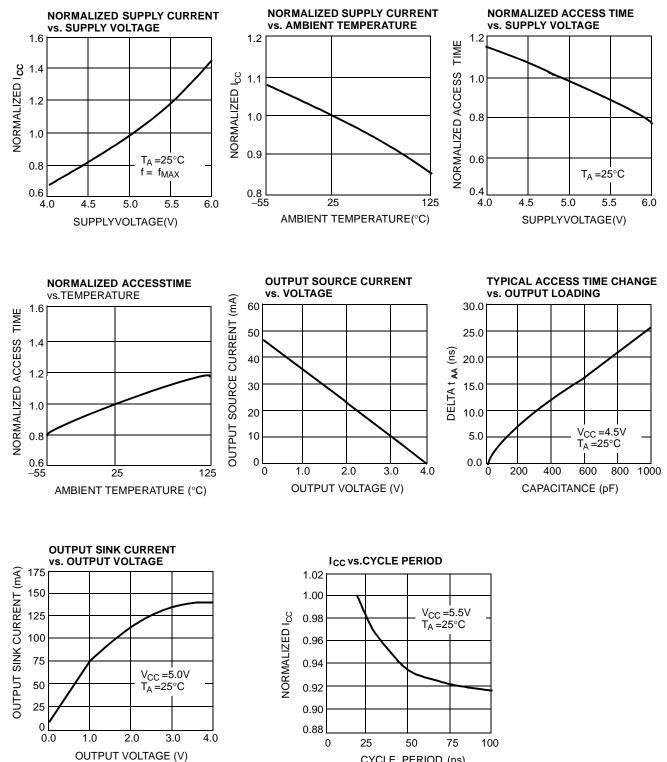
6. X = "don't care" but not to exceed V<sub>CC</sub>  $\pm$ 5%.



**Figure 1. Programming Pinouts** 



# **Typical DC and AC Characteristics**





# **Ordering Information**

Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
25	CY7C281A-25DC	D14	24-Lead (300-Mil) CerDIP	Commercial
	CY7C281A-25JC	J64	28-Lead Plastic Leaded Chip Carrier	
	CY7C281A-25PC	P13	24-Lead (300-Mil) Molded DIP	
30	CY7C281A-30DC	D14	24-Lead (300-Mil) CerDIP	Commercial
	CY7C281A-30JC	J64	28-Lead Plastic Leaded Chip Carrier	
	CY7C281A-30PC	P13	24-Lead (300-Mil) Molded DIP	
	CY7C281A-30DMB	D14	24-Lead (300-Mil) CerDIP	Military
45	CY7C281A-45DC	D14	24-Lead (300-Mil) CerDIP	Commercial
	CY7C281A-45JC	J64	28-Lead Plastic Leaded Chip Carrier	
	CY7C281A-45PC	P13	24-Lead (300-Mil) Molded DIP	
	CY7C281A-45DMB	D14	24-Lead (300-Mil) CerDIP	Military
	CY7C281A-45KMB	K73	24-Lead Rectangular Cerpack	]

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Speed (ns)	Ordering Code	Package Name	Package Type	Operating Range
25	CY7C282A-25PC	P11	24-Lead (600-Mil) Molded DIP	Commercial
30	CY7C282A-30PC	P11	24-Lead (600-Mil) Molded DIP	Commercial
	CY7C282A-30DMB	D12	24-Lead (600-Mil) CerDIP	Military
45	CY7C282A-45PC	P11	24-Lead (600-Mil) Molded DIP	Commercial
	CY7C282A-45DMB	D12	24-Lead (600-Mil) CerDIP	Military

# MILITARY SPECIFICATIONS Group A Subgroup Testing

# **DC Characteristics**

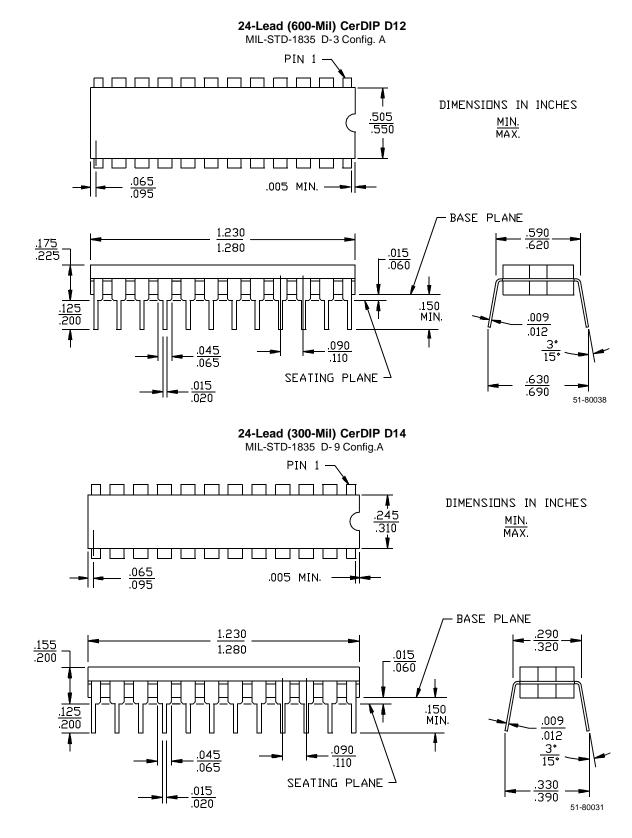
Parameter	Subgroups
V <sub>OH</sub>	1, 2, 3
V <sub>OL</sub>	1, 2, 3
V <sub>IH</sub>	1, 2, 3
V <sub>IL</sub>	1, 2, 3
I <sub>IX</sub>	1, 2, 3
I <sub>OZ</sub>	1, 2, 3
I <sub>CC</sub>	1, 2, 3

# **Switching Characteristics**

Parameter	Subgroups
t <sub>AA</sub>	7, 8, 9, 10, 11
t <sub>ACS</sub>	7, 8, 9, 10, 11

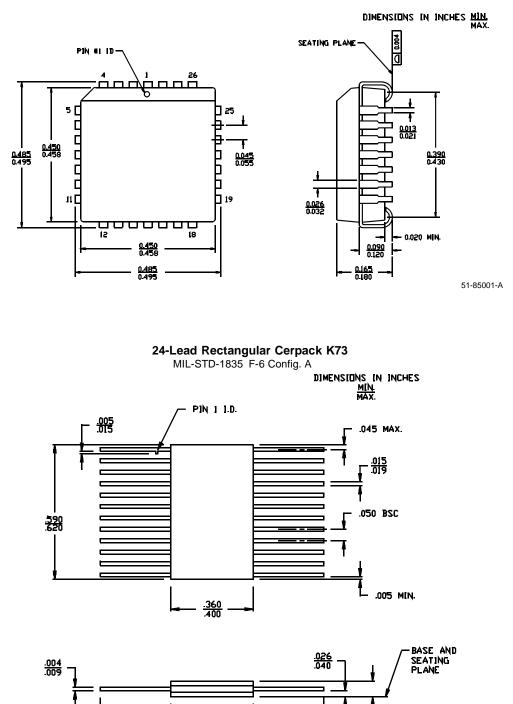


# **Package Diagrams**





## Package Diagrams (continued)



<u>260</u> 325

<u>060</u> 090

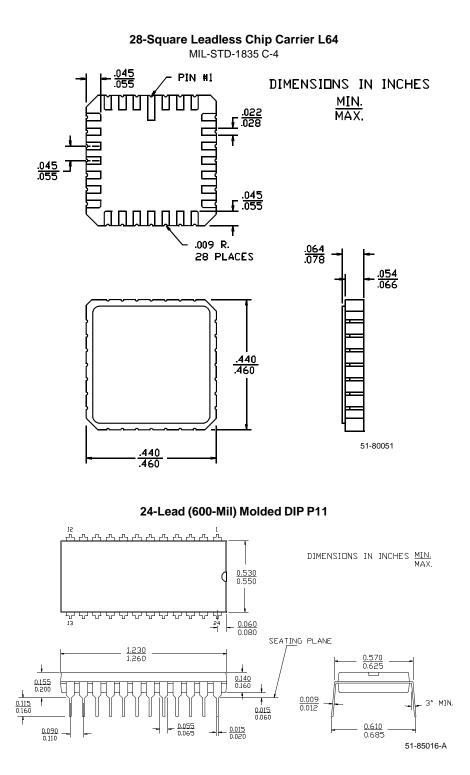
51-80060

28-Lead Plastic Leaded Chip Carrier J64

<u>260</u> 325



# Package Diagrams (continued)

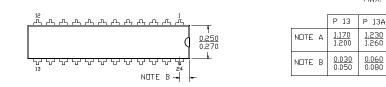


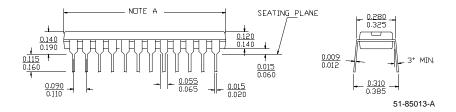


# Package Diagrams (continued)

#### 24-Lead (300-Mil) Molded DIP P13/P13A

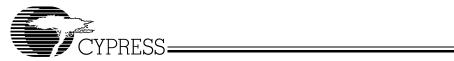
DIMENSIONS IN INCHES MIN. MAX.





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REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change	
**	113859	03/06/02	DSG	Change from Spec number: 38-00227 to 38-04003	